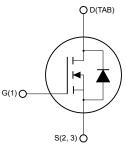


Automotive-grade N-channel 1200 V, 7.25 Ω typ., 1.5 A, MDmesh™ K5 Power MOSFET in an H²PAK-2 package

Features



H²PAK-2



DTG1S23NZ

Order code	V _{DS}	R _{DS(on)} max.	I _D	P _{TOT}
STH2N120K5-2AG	1200 V	10 Ω	1.5 A	60 W

- AEC-Q101 qualified
- Industry's lowest R_{DS(on)} x area
- Industry's best FoM (figure of merit)
- Ultra-low gate charge
- 100% avalanche tested

Applications

Switching applications

Description

This very high voltage N-channel Power MOSFET is designed using MDmesh™ K5 technology based on an innovative proprietary vertical structure. The result is a dramatic reduction in on-resistance and ultra-low gate charge for applications requiring superior power density and high efficiency.

Product status
STH2N120K5-2AG

Product summary ⁽¹⁾				
Order code STH2N120K5-2A0				
Marking	2N120K5			
Package	H ² PAK-2			
Packing	Tape and reel			

1. HTRB test was performed at 80% of V_{(BR)DSS} according to AEC-Q101 rev. C. All other tests were performed according to AEC-Q101 rev. D.



1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{GS}	Gate-source voltage	±30	V
I _D	Drain current (continuous) at T _{case} = 25 °C	1.5	Α
טי	Drain current (continuous) at T _{case} = 100 °C	1	A
I _{DM} ⁽¹⁾	Drain current (pulsed)	2.5	Α
P _{TOT}	Total dissipation at T _{case} = 25 °C	60	W
dv/dt ⁽²⁾	Peak diode recovery voltage slope	4.5	V/ns
dv/dt ⁽³⁾	MOSFET dv/dt ruggedness	50	V/IIS
T _{stg}	Storage temperature range	-55 to 150	°C
T _j	Operating junction temperature range	-33 to 130	

^{1.} Pulse width is limited by safe operating area.

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case	2.08	°C/W
R _{thj-pcb} ⁽¹⁾	Thermal resistance junction-pcb	30	C/VV

^{1.} When mounted on an 1-inch² FR-4, 2 Oz copper board.

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AR} ⁽¹⁾	Avalanche current, repetitive or not repetitive	0.5	Α
E _{AS} ⁽²⁾	Single pulse avalanche energy	80	mJ

^{1.} Pulse width is limited by T_{jmax} .

2. Starting $T_j = 25$ °C, $I_D = I_{AR}$, $V_{DD} = 50$ V

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^{2.} $I_{SD} \leq$ 1.5 A, di/dt = 100 A/ μ s, V_{DS} peak < $V_{(BR)DSS}$, V_{DD} = 80% $V_{(BR)DSS}$

^{3.} $V_{DS} \le 960 \text{ V}$



2 Electrical characteristics

(T_{case} = 25 °C unless otherwise specified)

Table 4. Static

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit	
V _{(BR)DSS}	Drain-source breakdown voltage	V _{GS} = 0 V, I _D = 1 mA	1200			V	
	Zana maka walkana dunin	V _{GS} = 0 V, V _{DS} = 1200 V			0.5		
I _{DSS}	I _{DSS} Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 1200 \text{ V},$ $T_{case} = 125 ^{\circ}\text{C}^{(1)}$			100	μA	
I _{GSS}	Gate-body leakage current	V _{DS} = 0 V, V _{GS} = ±20 V			±100	nA	
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 100 \mu A$	2	3	4	V	
R _{DS(on)}	Static drain-source on-resistance	V _{GS} = 10 V, I _D = 0.5 A		7.25	10	Ω	

^{1.} Defined by design, not subject to production test.

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance		-	124	-	
C _{oss}	Output capacitance	V _{DS} = 100 V, f = 1 MHz, V _{GS} = 0 V	-	13	-	pF
C _{rss}	Reverse transfer capacitance		-	0.5	-	
C _{o(tr)} ⁽¹⁾	Time-related equivalent capacitance	V _{GS} = 0 V, V _{DS} = 0 to 960 V	-	15	-	pF
C _{o(er)} ⁽²⁾	Energy-related equivalent capacitance	VGS = 0 V, VDS = 0 to 300 V	-	5	-	μΓ
R _G	Intrinsic gate resistance	f = 1 MHz, I _D = 0 A	-	16	-	Ω
Qg	Total gate charge	V _{DD} = 960 V, I _D = 1.5 A,	-	5.3	-	
Q _{gs}	Gate-source charge	V _{GS} = 0 to 10 V	-	0.8	-	nC
Q _{gd}	Gate-drain charge	(see Figure 13. Test circuit for gate charge behavior)	-	3.5	-	

^{1.} $C_{o(tr)}$ is a constant capacitance value giving the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	$V_{DD} = 600 \text{ V}, I_D = 0.75 \text{ A},$	-	10.3	-	
t _r	Rise time	$R_G = 4.7 \Omega$, $V_{GS} = 10 V$ (see Figure 12. Test circuit for resistive load switching times	-	7.8	-	
t _{d(off)}	Turn-off delay time		-	34	-	ns
t _f	Fall time	and Figure 17. Switching time waveform)	-	39	-	

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^{2.} $C_{o(er)}$ is a constant capacitance value giving the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .



Table 7. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current		-		1.5	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)		-		2.5	Α
V _{SD} ⁽²⁾	Forward on voltage	V _{GS} = 0 V, I _{SD} = 1.5 A	-		1.5	V
t _{rr}	Reverse recovery time	I _{SD} = 1.5 A, di/dt = 100 A/μs, V _{DD} = 60 V	-	350		ns
Q _{rr}	Reverse recovery charge		-	1.35		μC
I _{RRM}	Reverse recovery current	(see Figure 14. Test circuit for inductive load switching and diode recovery times)	-	7.7		А
t _{rr}	Reverse recovery time	$I_{SD} = 1.5 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$	-	600		ns
Q _{rr}	Reverse recovery charge	V _{DD} = 60 V, T _j = 150 °C (see Figure 14. Test circuit for inductive load switching and diode recovery times)	-	2.09		μC
I _{RRM}	Reverse recovery current		-	7.7		А

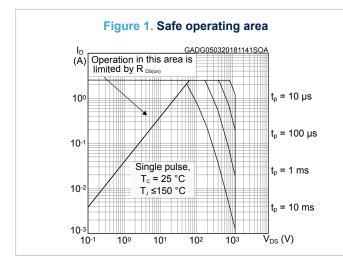
^{1.} Pulse width is limited by safe operating area.

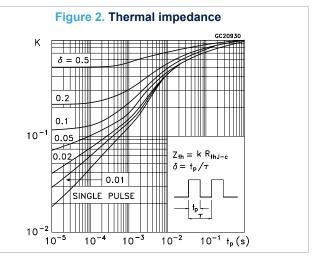
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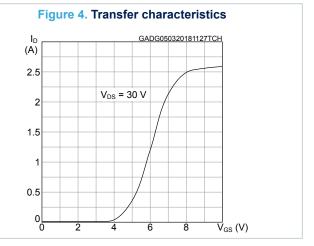
^{2.} Pulse test: pulse duration = $300 \mu s$, duty cycle 1.5%.

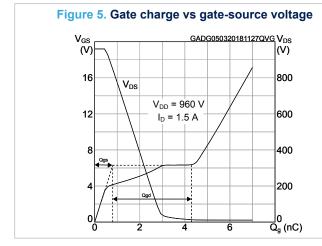


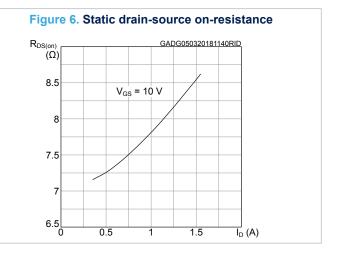
2.1 Electrical characteristics (curves)











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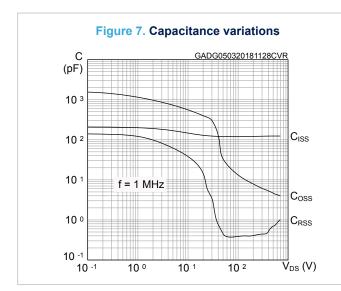
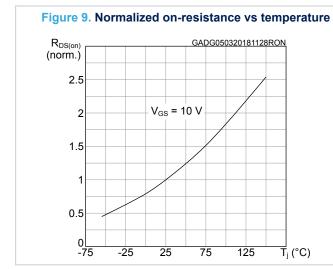
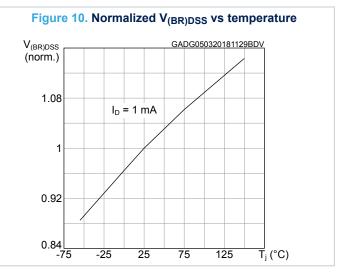
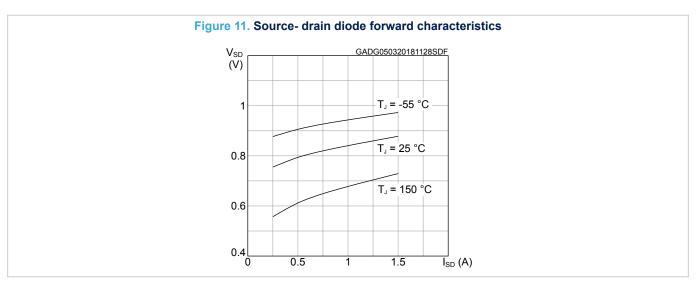


Figure 8. Normalized gate threshold voltage vs temperature $V_{GS(th)} = \frac{V_{GS(th)}}{I_{D}} = 100 \ \mu A$ 0.8 0.4 -75 -25 25 75 125 $T_{j} (^{\circ}C)$







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3 Test circuits

Figure 12. Test circuit for resistive load switching times

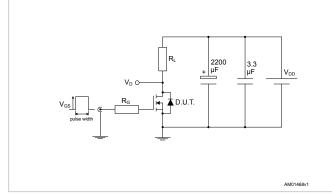


Figure 13. Test circuit for gate charge behavior

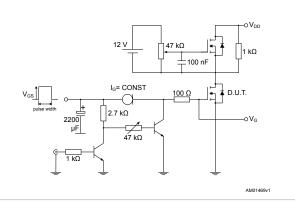


Figure 14. Test circuit for inductive load switching and diode recovery times

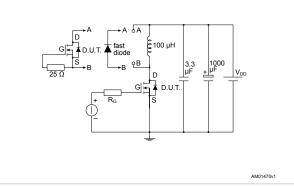


Figure 15. Unclamped inductive load test circuit

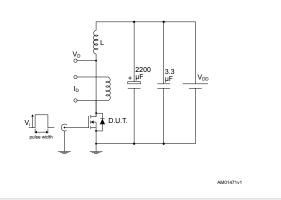


Figure 16. Unclamped inductive waveform

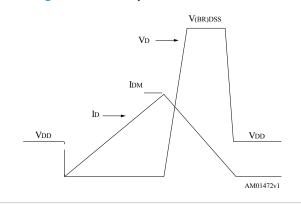
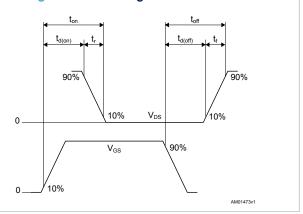


Figure 17. Switching time waveform



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4 Package information

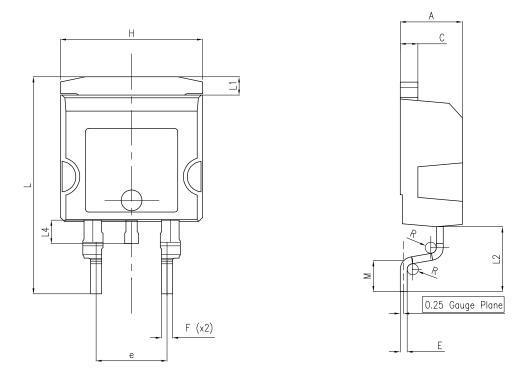
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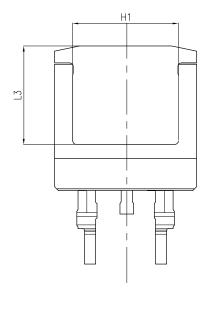
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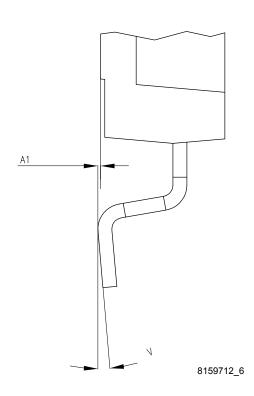


4.1 H²PAK-2 package information

Figure 18. H²PAK-2 package outline







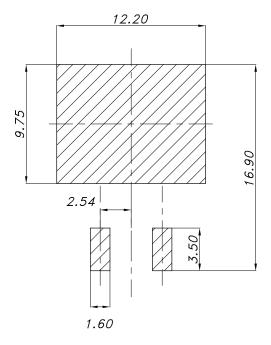
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Table 8. H²PAK-2 package mechanical data

Dim.		mm	
Dilli.	Min.	Тур.	Max.
A	4.30		4.70
A1	0.03		0.20
С	1.17		1.37
е	4.98		5.18
E	0.50		0.90
F	0.78		0.85
Н	10.00		10.40
H1	7.40		7.80
L	15.30	-	15.80
L1	1.27		1.40
L2	4.93		5.23
L3	6.85		7.25
L4	1.5		1.7
M	2.6		2.9
R	0.20		0.60
V	0°		8°

Figure 19. H²PAK-2 recommended footprint



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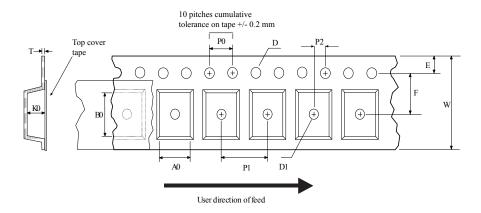
Note: Dimensions are in mm.

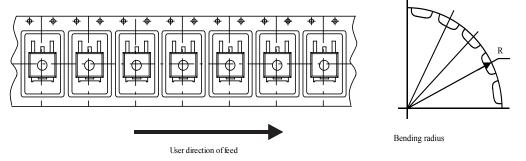
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4.2 Packing information

Figure 20. Tape outline





AM08852v2

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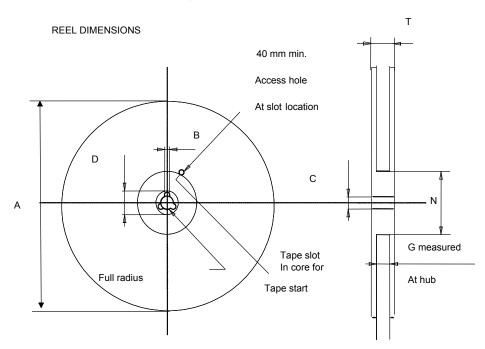


Figure 21. Reel outline

Table 9. Tape and reel mechanical data

	Tape			Reel	
Dim.	1	mm	Dim.	m	m
Dilli.	Min.	Max.		Min.	Max.
A0	10.5	10.7	Α		330
В0	15.7	15.9	В	1.5	
D	1.5	1.6	С	12.8	13.2
D1	1.59	1.61	D	20.2	
Е	1.65	1.85	G	24.4	26.4
F	11.4	11.6	N	100	
K0	4.8	5.0	Т		30.4
P0	3.9	4.1			
P1	11.9	12.1	Base of	quantity	1000
P2	1.9	2.1	Bulk quantity		1000
R	50				
Т	0.25	0.35			
W	23.7	24.3			

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Revision history

Table 10. Document revision history

Date	Version	Changes
23-Mar-2018	1	Initial release. The document status is preliminary data.
30-Jul-2018	2	The document status was promoted from preliminary to production data. Updated title and features on cover page.
31-Jul-2018	3	Updated the current table. The date for revision 2 was erroneously reported as "19-Jun-2018" instead of "30-Jul-2018".
05-Sep-2018	4	Updated I _{DSS} parameter in Table 4. Static.

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